

Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	250				
R _{DS(on)} (Ω)	V _{GS} = 10 V 1.1				
Q _g (Max.) (nC)	14				
Q _{gs} (nC)	2.7				
Q _{gd} (nC)	7.8				
Configuration	Single				

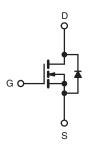
FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	250		
Gate-Source Voltage			V_{GS}	± 20	_ V	
Continuous Drain Current	T _C :	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$		4.4	A	
	V _{GS} at 10 V	T _C = 100 °C	I _D	2.8		
Pulsed Drain Current ^a			I _{DM}	14		
Linear Derating Factor				0.40	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	100	mJ	
Repetitive Avalanche Current ^a			I _{AR}	4.4	Α	
Repetitive Avalanche Energy ^a			E _{AR}	5.0	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P_{D}	50	W	
Peak Diode Recovery dV/dt ^c			dV/dt	4.8	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) for 10 s			-	300 ^d		
Mounting Toyaus	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 8.3 mH, R_g = 25 Ω , I_{AS} = 4.4 A (see fig. 12).
- c. $I_{SD} \le 4.4$ A, $dI/dt \le 90$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.5		

PARAMETER	SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	
Static					•		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		250	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I _D = 1 mA		0.36	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = \	$V_{DS} = V_{GS}, I_D = 250 \mu A$		-	4.0	V
Gate-Source Leakage	I _{GSS}	Vo	_{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		250 V, V _{GS} = 0 V	-	-	25	μA
			V _{GS} = 0 V, T _J = 125 °C	-	-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.6 A ^b	-	1.1	-	Ω
Forward Transconductance	9 _{fs}	$V_{DS} = 5$	50 V, I _D = 2.6 A ^b	1.5	-	-	S
Dynamic					1	T	1
Input Capacitance	C_{iss}	\	$V_{GS} = 0 V$,		260	-	
Output Capacitance	C _{oss}		DS = 25 V,	-	77	-	pF
Reverse Transfer Capacitance	C _{rss}	1 = 1.0	MHz, see fig. 5	-	15	-	
Total Gate Charge	Q_g		$V_{GS} = 10 \text{ V}$ $I_D = 4.4 \text{ A}, V_{DS} = 200 \text{ V},$ see fig. 6 and 13 ^b		-	14	nC
Gate-Source Charge	Q_gs	V _{GS} = 10 V			-	2.7	
Gate-Drain Charge	Q_{gd}			-	-	7.8	
Turn-On Delay Time	t _{d(on)}	$V_{DD}=125~V,~I_D=4.4~A,$ $R_g=18~\Omega,~R_D=28~\Omega,~see~fig.~10^b$		-	7.0	-	ns .
Rise Time	t _r			-	13	-	
Turn-Off Delay Time	t _{d(off)}			-	20	-	
Fall Time	t _f			-	12	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") fro	Between lead, 6 mm (0.25") from		4.5	-	
Internal Source Inductance	L _S	package and center of die contact		-	7.5	-	nH
Drain-Source Body Diode Characteristic	s				•		
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4.4	A
Pulsed Diode Forward Current ^a	I _{SM}			ı	-	14	^
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 4.4 A, V _{GS} = 0 V ^b		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	$T_{\rm J} = 25~{\rm ^{\circ}C}, \ I_{\rm F} = 4.4~{\rm A}, \ {\rm dI/dt} = 100~{\rm A/\mu s^b}$		-	200	400	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.93	1.9	μC
Forward Turn-On Time	t _{on}	Intrinsic turn	on in do	minated h	ov L - and	1 \	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

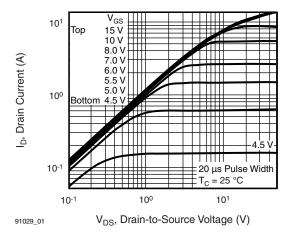


Fig. 1 - Typical Output Characteristics, $T_C = 25$ °C

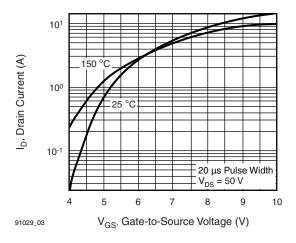


Fig. 3 - Typical Transfer Characteristics

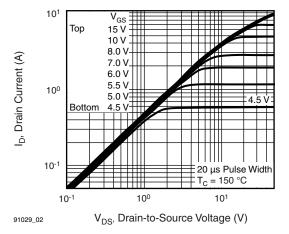


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

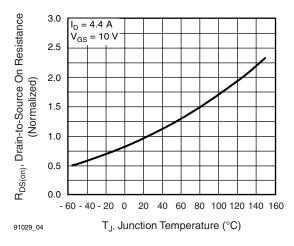


Fig. 4 - Normalized On-Resistance vs. Temperature



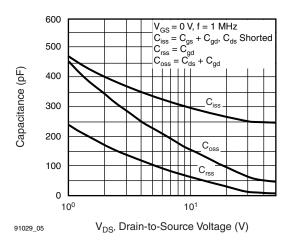


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

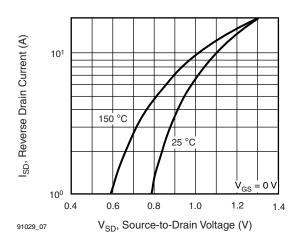


Fig. 7 - Typical Source-Drain Diode Forward Voltage

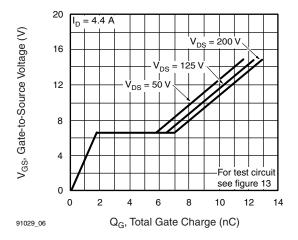


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

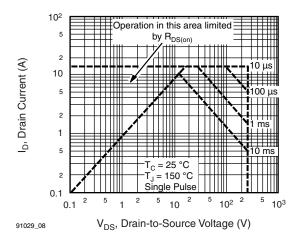


Fig. 8 - Maximum Safe Operating Area



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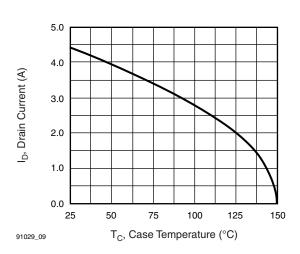


Fig. 9 - Maximum Drain Current vs. Case Temperature

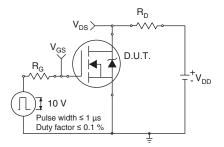


Fig. 10a - Switching Time Test Circuit

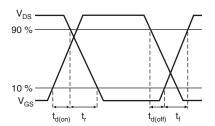


Fig. 10b - Switching Time Waveforms

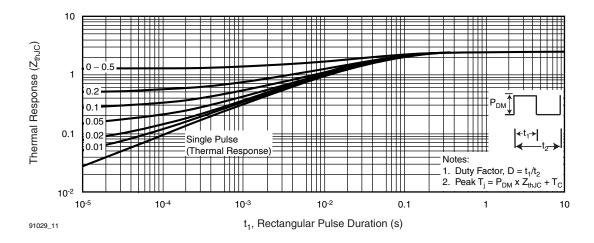


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



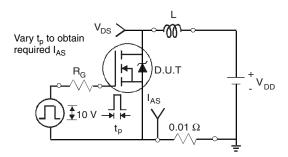


Fig. 12a - Unclamped Inductive Test Circuit

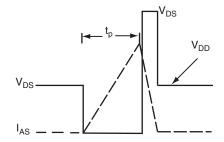


Fig. 12b - Unclamped Inductive Waveforms

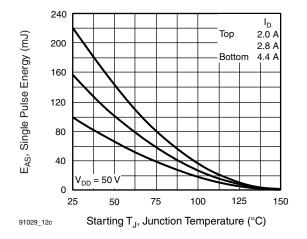


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

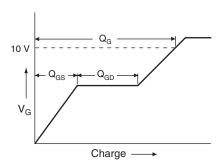


Fig. 13a - Basic Gate Charge Waveform

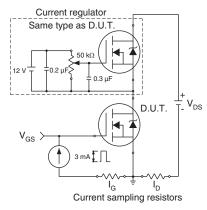
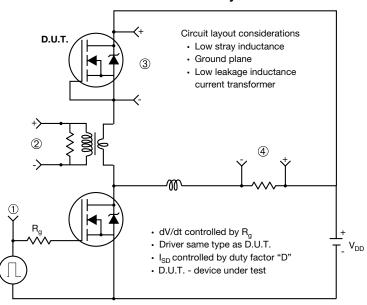


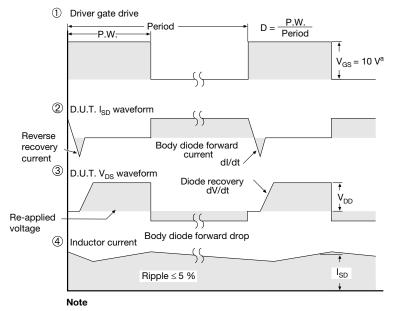
Fig. 13b - Gate Charge Test Circuit



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Peak Diode Recovery dV/dt Test Circuit



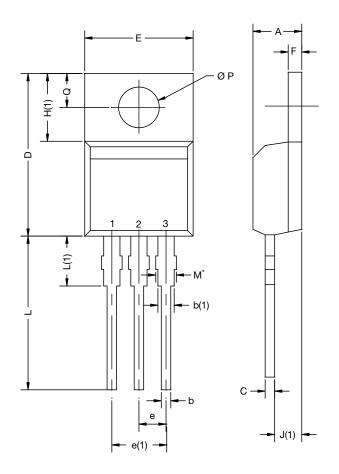


a. $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 14 - For N-Channel



TO-220-1



DIM.	MILLIN	IETERS	INCHES		
DIIVI.	MIN.	MAX.	MIN.	MAX.	
А	4.24	4.65	0.167	0.183	
b	0.69	1.02	0.027	0.040	
b(1)	1.14	1.78	0.045	0.070	
С	0.36	0.61	0.014	0.024	
D	14.33	15.85	0.564	0.624	
Е	9.96	10.52	0.392	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.10	6.71	0.240	0.264	
J(1)	2.41	2.92	0.095	0.115	
L	13.36	14.40	0.526	0.567	
L(1)	3.33	4.04	0.131	0.159	
ØΡ	3.53	3.94	0.139	0.155	
Q	2.54	3.00	0.100	0.118	
ECN: X15-0364-Rev. C, 14-Dec-15 DWG: 6031					

Note

 $\bullet~M^{\star}=0.052$ inches to 0.064 inches (dimension including protrusion), heatsink hole for HVM



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